## UNITED STATES PATENT AND TRADEMARK OFFICE **CERTIFICATE OF CORRECTION**

PATENT NO.

: 6,929,530 B1

Page 1 of 2

APPLICATION NO. : 09/616794

DATED

: August 16, 2005

INVENTOR(S)

: Jason B. Elledge

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

		Should Read
Column 5, Line 4	"interferrometer"	interferometer
Column 7, Line 32	"system in defined"	system is defined
Column 8, Line 28	"substrate assembly the	substrate assembly, the
	second view site"	second view site
Column 8, Line 43	"claim 1 wherein the"	claim 1 wherein
Column 9, Line 5	"planarizing medium—"	planarizing medium
Column 9, Line 13	"located at first area"	located at a first area
Column 9, Line 27	"substrate assembly the	substrate assembly, the
	second view"	second view
Column 9, Line 32	"the-planarizing medium"	the planarizing medium
Column 10, Lines 22-23	"with the first elongated	with the first elongated
	slot through the	slot
	planarizing medium."	
Column 10, Line 61	"substrate assembly the	substrate assembly, the
	second view"	second view
Column 10, Line 66	"and a under surface,"	and an under surface,

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## Should Read

Column 11, Line 44

"plurality of opening."

--plurality of openings.--

Signed and Sealed this

Eighth Day of May, 2007

JON W. DUDAS Director of the United States Patent and Trademark Office